

**Notice of References Cited**

Application/Control No.

10/574,219

Applicant(s)/Patent Under  
Reexamination  
SCHULZ ET AL.

Examiner

LUKE E. KARPINSKI

Art Unit

1616

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,042,816 A	03-2000	Shen, Yan-Fei	424/65
*	B	US-2002/0077372 A1	06-2002	GERS-BARLAG et al.	516/98
*	C	US-2005/0265940 A1	12-2005	Okada, Toru	424/066
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.